

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/047,060	BAICHWAL ET AL.	
Examiner	Art Unit	
Carlos A. Azpuru	1615	

SEARCHED					
Class	Subclass	Date	Examiner		
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
424	434	9/28/06	CA		
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	49-500				
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
inventor neme search	9/20/2006	de		